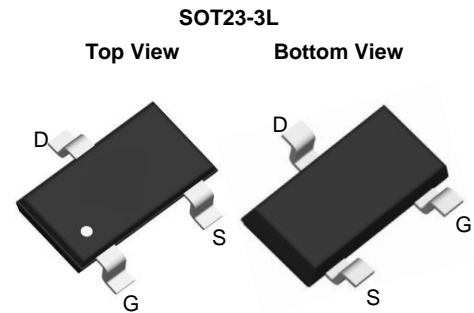


P-Channel Enhancement Mode MOSFET

Features

- -20V / -3A
- $R_{DS(ON)}=56m\Omega$ (typ) @ $V_{GS}=-4.5V$
 $R_{DS(ON)}=82m\Omega$ (typ) @ $V_{GS}=-2.5V$
- 100% UIS & RG Tested
- Reliable and Rugged
- Lead Free and Green Devices Available (RoHS Compliant)

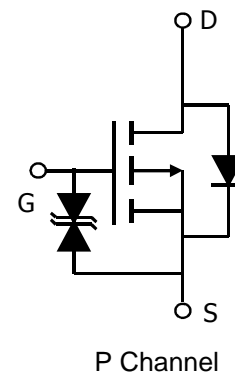


Applications

- Power Management for Industrial DC/DC Converters

Marking

Marking	AD****
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ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless otherwise noted)

Symbol	Parameter	Typical	Unit
V_{DSS}	Drain-Source Voltage	-20	V
V_{GSS}	Gate-Source Voltage	± 12	V
I_D	Continuous Drain Current ($T_J=150^\circ C$)	$V_{GS}=-4.5V$ -3.0	A
I_{DM}	Pulsed Drain Current	-15	A
I_S	Continuous Source Current (Diode Conduction)	-1.6	A
P_D	Power Dissipation	$T_A=25^\circ C$	1.4
		$T_A=70^\circ C$	0.9
T_J	Operation Junction Temperature	150	$^\circ C$
T_{STG}	Storage Temperature Range	-55~+150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction to Ambient	120	$^\circ C/W$

ELECTRICAL CHARACTERISTICS ($T_A=25^\circ\text{C}$ Unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
Static Parameters						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-20			V
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu A$	-0.4		-1	V
I_{GSS}	Gate Leakage Current	$V_{DS}=0V, V_{GS}=\pm 12V$			± 100	nA
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-20V, V_{GS}=0$			-1	uA
		$V_{DS}=-20V, V_{GS}=0$ $T_J=55^\circ\text{C}$			-10	
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS}=-4.5V, I_D=-3.0A$		56	80	m Ω
		$V_{GS}=-2.5V, I_D=-2.6A$		82	100	
		$V_{GS}=-1.8V, I_D=-1.0A$			160	
Gfs	Forward Transconductance	$V_{DS}=-5V, I_D=-2.8A$		6.5		S
Source-Drain Diode						
V_{SD}	Diode Forward Voltage	$I_S=-1.6A, V_{GS}=0V$		-0.7	-1.2	V
Dynamic Parameters						
Q_g	Total Gate Charge	$V_{DS}=-10V$ $V_{GS}=-4.5V$ $I_D=-3.2A$		7	10	nC
Q_{gs}	Gate-Source Charge			1.8		
Q_{gd}	Gate-Drain Charge			2		
C_{iss}	Input Capacitance	$V_{DS}=-10V$ $V_{GS}=0V$ $f=1\text{MHz}$		415		pF
C_{oss}	Output Capacitance			223		
C_{rss}	Reverse Transfer Capacitance			87		
$T_{d(on)}$	Turn-On Time	$V_{DS}=-10V$ $R_L=10\Omega$		13	25	nS
T_r				36	60	
$T_{d(off)}$	Turn-Off Time	$I_D=-1A$ $V_{GEN}=-4.5V$ $R_G=6\Omega$		42	70	
T_f				34	60	

TYPICAL CHARACTERISTICS (25 °C Unless Note)

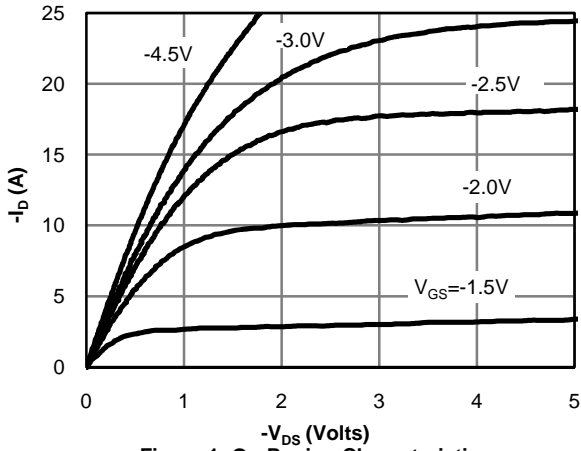


Figure 1: On-Region Characteristics

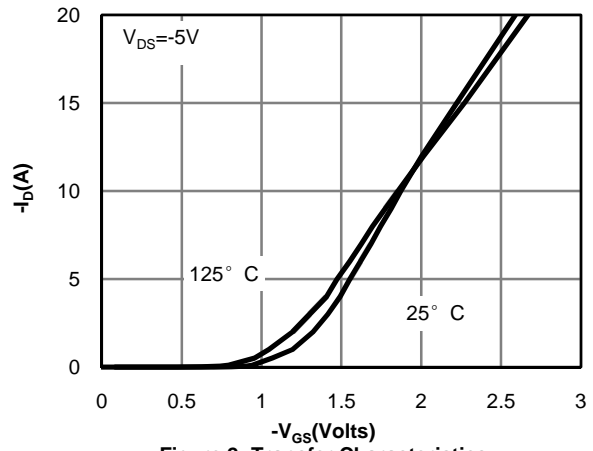


Figure 2: Transfer Characteristics

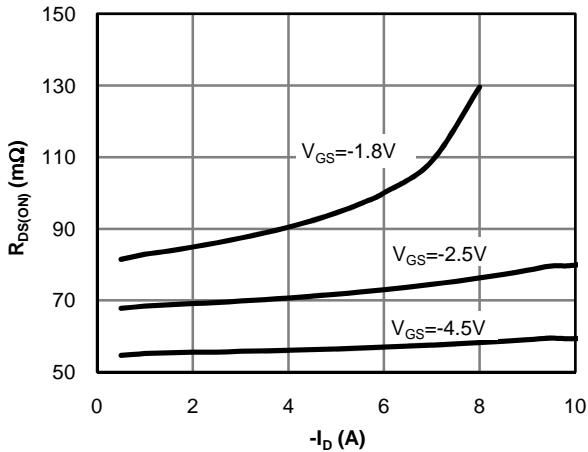


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

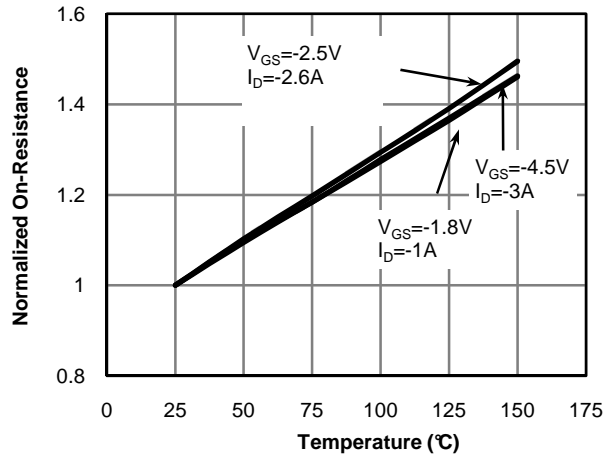


Figure 4: On-Resistance vs. Junction Temperature

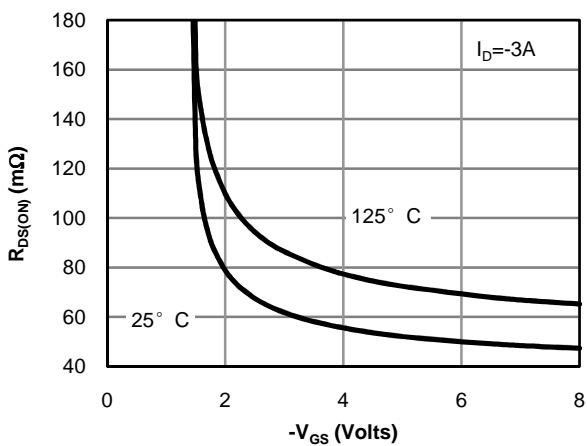


Figure 5: On-Resistance vs. Gate-Source Voltage

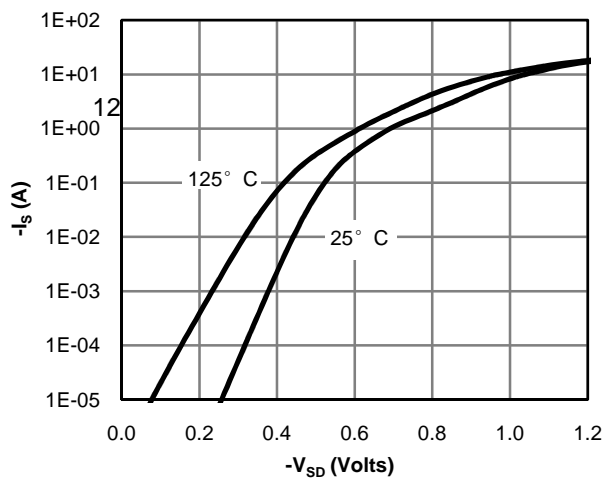


Figure 6: Body-Diode Characteristics

TYPICAL CHARACTERISTICS (continuous)

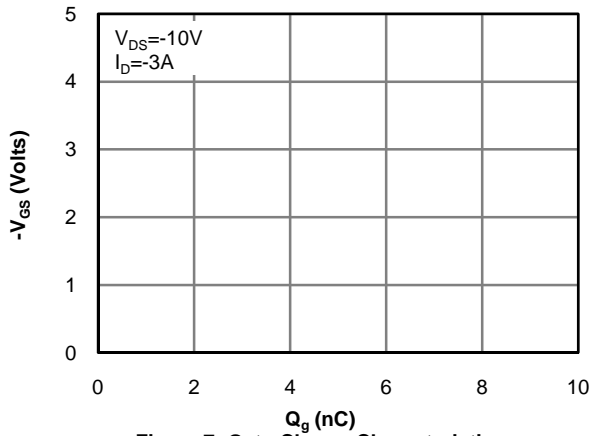


Figure 7: Gate-Charge Characteristics

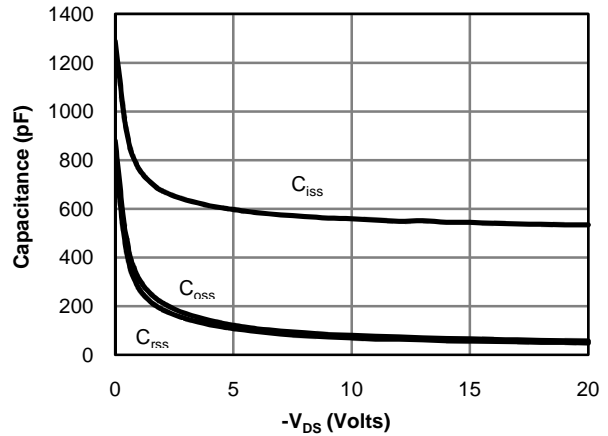


Figure 8: Capacitance Characteristics

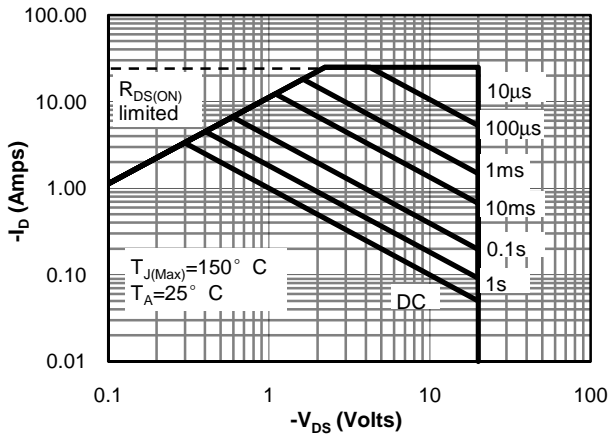


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

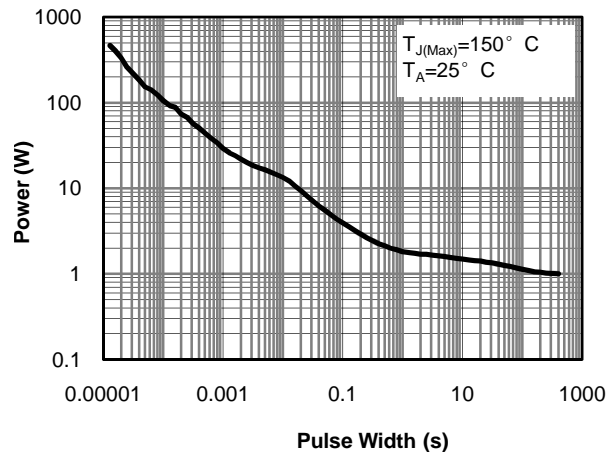


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

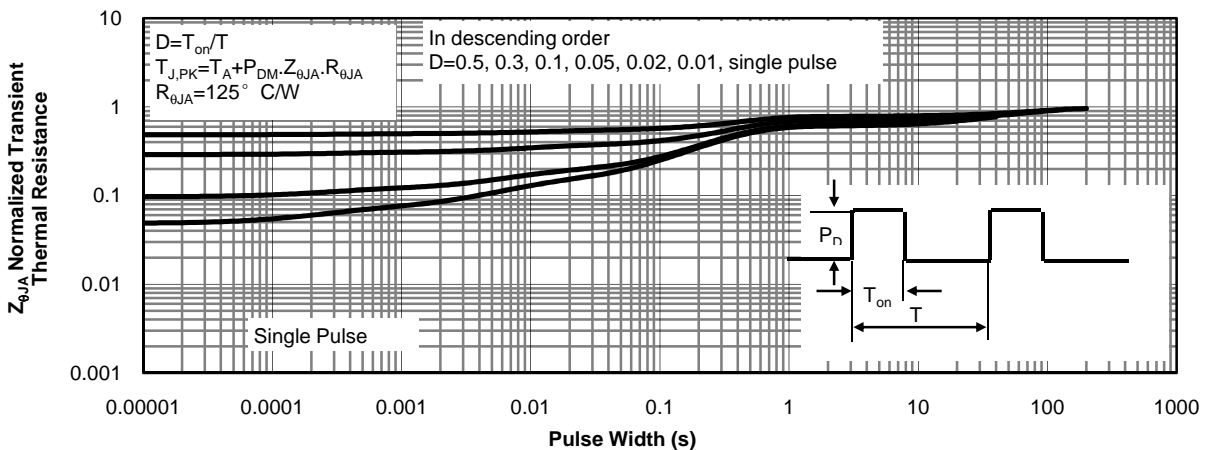
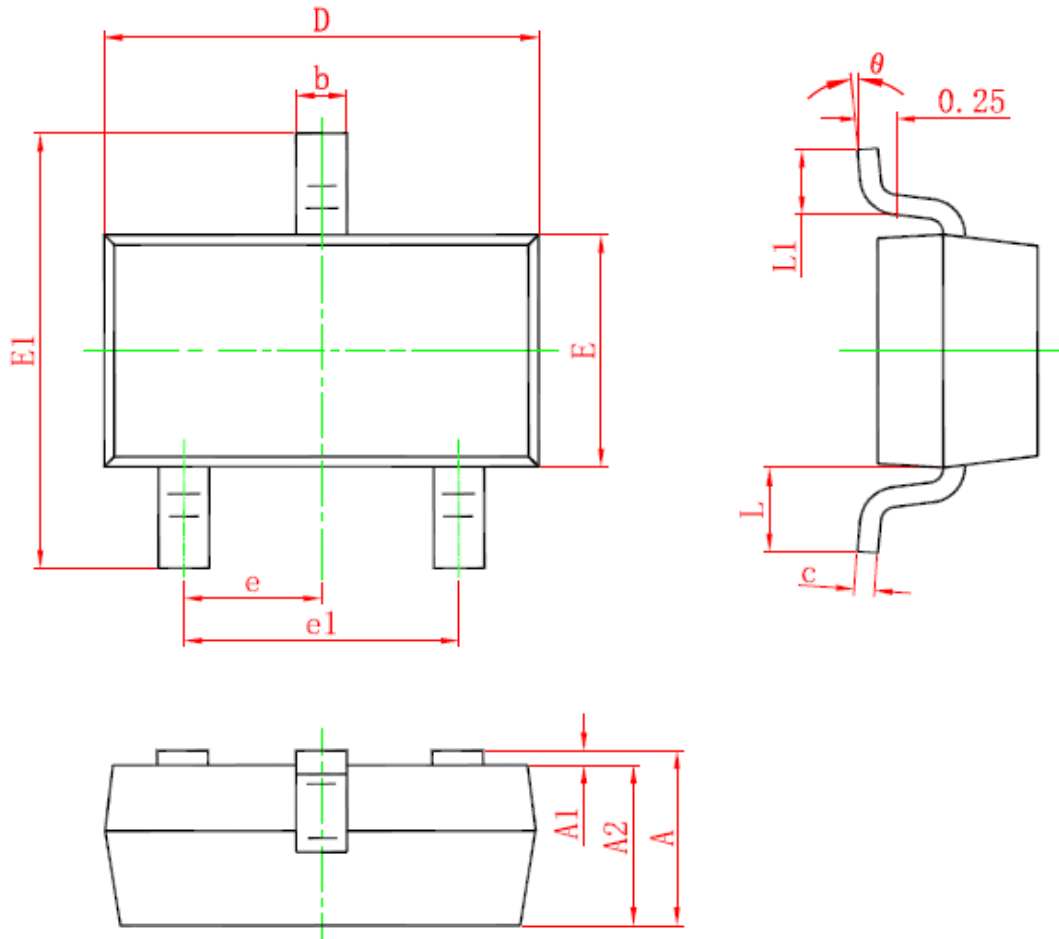


Figure 11: Normalized Maximum Transient Thermal Impedance (Note E)

SOT23-3L PACKAGE OUTLINE DIMENSIONS



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
c	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
e	0.950 TYP.		0.037 TYP.	
e1	1.800	2.000	0.071	0.079
L	0.550 REF.		0.022 REF.	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

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